



# *Materials Characterization from Processing to Performance*

**2010 ASM Annual Symposium**

**May 18 & 19, 2010**

Steinmetz Hall, GE Global Research, Niskayuna, NY

## **Session Topics**

- Characterization Methods from Nano to Macro
- 3D Characterization and Modeling
- Assessing Environmental Degradation
- Processing Effects on Materials Performance

Symposium Reception, Dinner and Lecture  
May 18<sup>th</sup> at the Glen Sanders Mansion

Gene E. Ice

*Oak Ridge National Laboratory Corporate Fellow*

*Oak Ridge National Laboratory*

*The Coming Revolution: A Convergence of Characterization and Modeling Length Scales*

Fees (includes lunches and symposium dinner)

Professionals: \$270

Retirees: \$65

Students: \$25

Dinner only cost:

Professionals: \$20; Retirees: \$15; Students: \$10

**Pre-register online by May 13<sup>th</sup>:** <http://www.asm-easternny.org>

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